## **The Physics of Current Measurement**

## GMWAssociates

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#### Agenda



#### **GMW Overview**

- Current Transducers & Calibration Services
- Magnetic Field Transducers & Calibration Services
- Electromagnet Systems



#### **Current Transducer Technologies**

- Passive Current Transformers
- Active Current Transformers
- Rogowski Coils
- Flux-gate DC Current Transformers
- Hall Effect Current Sensors



#### **Common Issues**

- Transducer Termination Impedance
- Uncertainty Analysis



#### **GMW** Associates – Overview

GMW is the designer, integrator, and distributor of Magnetic Systems and Instrumentation based on Magnetics

- Founded in 1982
- Staff of 20, 50% with technical degrees
- Headquarters in San Carlos, California (30 miles from San Francisco)
- Background in Accelerator Physics, MRI, Instrumentation, Materials Research, and Power Electronics



#### Instrumentation

- Electric Current Measurement
- Magnetic Field Measurement
- Particle Beam Diagnostics

#### **Calibration and Service**

- 17025 Accredited Current Transducer Calibrations
- Magnetic Field Mapping
- Magnetic Site Survey

#### **Electromagnet Systems**

- Dipole Magnets
- Projected Field Magnets
- High-Uniformity Magnets
- Magnetic Modeling & Design

### **GMW Current Transducers & Calibration Services**

#### **Distribute in North America:**

- Flux-gate DCCTs from Danisense (Denmark)
- Rogowski Coils from PEM (UK)
- Passive CTs from MagneLab (US)
- Particle Beam Diagnostics from Bergoz (France)

#### Manufacture & Distribute:

Hall Effect-based Clip/Clamp-on Sensors

#### 17025 Accredited Calibration Services

- DC up to 11 kA
- AC up to 8 kA and up to 400 Hz
- Onsite Services

#### **GMW Current Calibration Lab**





### Magnetic Field Transducers & Calibration Services

- Distribute in North America:
  - Low-Field Flux-gate Magnetometers from Bartington (UK)
  - Hall Effect Digital Teslameters from Senis & Metrolab (Switzerland)
  - Analog and Digital Magnetic Field Transducers from Senis (Switzerland)
  - Hall Effect Magnetic Field Mappers from Senis & Metrolab (Switzerland)
  - NMR Teslameters & Magnetic Field Cameras from Metrolab (Switzerland)

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- Services:
  - Magnetic field transducer calibration
  - Magnet mapping
  - Magnetic site survey
  - Magnetic field exposure testing











#### Senis Mapper @ GMW



#### **Electromagnet Systems**



#### **GMW & Bartington Helmholtz Coils**

- Environmental Field Exposure
- Magnetic Field Immunity Testing
- Shielded versions available



#### **GMW Dipole Electromagnets**

- Material Characterization
- Hall Effect Sensor Calibration



#### GMW Projected Field Electromagnets

Sensor Testing



## **Current Transducer Technologies**

### Current Shunts vs Galvanically Isolated Sensors

#### **Current Shunts** Directly Measure Current

- Power Dissipation  $\propto I_p^2$
- Inaccuracies due to heating at high  $I_p$
- Limited dynamic range in high  $I_p$  shunts
- High Voltage Safety concerns

#### Galvanically Isolated Sensors Measure Magnetic Field

#### **Transformer-based:**

- Passive Current Transformers (AC, highest hi-freq cut-off)
- Active Current Transformers (AC, highest sensitivity)
- Rogowski Coils (AC, moderate BW for very high currents)
- Closed-Loop Flux-Gate DCCTs (DC+AC, ppm-level accuracy)

#### **Core-less Hall Effect-based**

- Low-cost
- DC + AC up to 10s kHz
- ~1% accuracy
- Very high current

## Passive Current Transformers (CTs)

For AC & Pulsed Measurements

### Passive Current Transformer Model

- Simplest Galvanically isolated current sensor
- AC Only BW can exceed 1 GHz
- Transformer with output  $R_{\rm L}=50~\Omega$  termination resistor
- $V_o \cong \frac{R_L}{N} I_p$  within the pass band
- Circuit Model:
  - $L_M$ : Primary magnetizing inductance
  - C<sub>S</sub>: Secondary parasitic capacitance
  - Ignored leakage inductance, coil resistance, cable



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#### Dana pass men

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Ideal Xformer

#### Passive CT Frequency and Time Response

• 
$$\frac{V_o}{I_p} = \frac{Z_{eq}}{N} = \frac{1}{N} \frac{j\omega L'_M}{1 - \left(\omega \frac{L'_M}{R_L}\right)(\omega R_L C_S) + j\omega \frac{L'_M}{R_L}} = \begin{cases} \frac{j\omega L'_M}{N} & \omega \ll R_L/L'_M \\ \frac{1}{j\omega C_S N} & \omega \ll 1/R_L C_S \\ \frac{R_L}{N} & R_L/L'_M \ll \omega \ll 1/R_L C_S \end{cases}$$



• Low frequency cutoff causes droop  $t_d = \frac{\ln 0.9 - \ln 0.1}{\omega_L} \approx \frac{1}{3 f_L}$  need to maximize  $L'_M \to \text{high } \mu_r$ , N

Measuring low current  $\rightarrow$  high sensitivity  $\rightarrow$  low  $N \rightarrow$  low  $L'_M \rightarrow$  high  $f_L$  and significant droop

- High frequency cutoff restricts rise time to  $t_r = \frac{\ln 0.9 \ln 0.1}{\omega_H} \approx \frac{1}{3 f_H}$  need to minimize  $C_s$ 
  - Measuring high current  $\rightarrow$  low sensitivity  $\rightarrow$  high  $N \rightarrow$  high  $C_S \rightarrow$  low  $f_H$  and slow rise time
- R<sub>L</sub> also affects BW
- Waveforms get skewed:





### MagneLab CTs & Bergoz FCTs

#### MagneLab CT

- Sensitivity 0.025 to 2.5 V/A into 50  $\Omega$
- Low Cutoff down to **0.5 Hz** (for low sensitivity)
- High Cutoff up to **500 MHz** (for high sensitivity)
- uA to 20 kA peak
- ID from 0.25 in to 2 in



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#### Bergoz FCT

- Sensitivity 0.25 to 5 V/A into 50  $\Omega$
- Low Cutoff down to 1.6 kHz
- High Cutoff up to 1.5 GHz
- Up to 2 kA peak
- ID from 22.2 mm to 198.4 mm





### Passive CT Pitfalls

- CT specs typically guaranteed only for 50 Ohm termination
- There is finite insertion impedance (order of 100 nH) that can perturb DUT
  - Added inductance can cause oscillations with package parasitics in SiC/GaN transistors switching
- Noise can get coupled through CT case, need Common Mode Chokes for noisy environments
- Noise due to resistor even though no active electronics (10 uVrms at 300 K over 500 MHz)
- **DC current** will cause the  $\omega_L$  to go up, droop will increase
  - Susceptivity to external magnetic fields
  - Unipolar pulses may need a negative DC bias
- I \* t needs to be higher than primary pulse charge



Lower cut-off frequency dependence to DC primary current

## Active Current Transformers

For Low-Current AC Measurements

### Active (Hereward) Transformer

- Passive CTs are limited:
  - Cannot measure **long pulses** due to droop /  $\omega_L$
  - Sensitivity limited by minimum amount of turns
- In an Active CT coil load is only it's winding resistance  $R_w$

• 
$$\omega'_L = \frac{R_w}{L'_M} \ll \frac{50 \,\Omega}{L'_M}$$

- $\omega_H$  additionally limited by Opamp finite Gain-BW
- $V_o = -\frac{I_p}{N}R_f$
- Sensitivity can be high, determined by  $R_f$  & opamp
- Another variation uses feedback coil



### Bergoz ACCT

#### **Bergoz ACCT**

- Sensitivity 5 V/A to **10 kV/A** into high impedance
  - 3-range electronics as an option
- Low Cutoff < 3 Hz</li>
- High Cutoff up to 3 MHz
- Full scale range 1 mA to 2 A
- ID from 22.2 mm to 198.4 mm

In-Flange for beam measurements





In-air

Single-range electronics







# Rogowski Coils

For High-Current AC Measurements

### Rogowski Coil Principle of Operation

- Rogowski coil is a Core-Less Narrow-Band transformer operating before resonance
  - Output voltage is derivative of primary current need integrator electronics
- Integrator results in **Band-Pass Filter** 
  - Low cut-off causes droop
  - High cut-off limits rise time
- Can measure currents up to 100s of kA
  - No saturation because core-less
  - No overcurrent damage

• Limited by  $\frac{dI_p}{dt}\Big|_{pk} \& \frac{dI_p}{dt}\Big|_{rms}$ 



### Rogowski Coil Circuit Analysis (PEM Architecture)



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### Rogowski Coil Circuit Analysis Cont'd (PEM Architecture)



#### PEM Rogowski Coil Product Lines



**CWT Ultra Mini** 1.7 mm cross-section 1.2 kV isolation 30 A to 6 kA 2 Hz to 30 MHz



**CWT Mini50HF** 3.5 mm cross-section 2 kV isolation 30 A to 30 kA 1 Hz to **50 MHz** 



CWT LF Miniature & Standard Coils 60 A to 300 kA 8 mHz to 12 MHz



**CWT** 8.5 mm cross-section 10 kV isolation 30 A to 300 kA 0.03 Hz to 16 MHz



LFR Dual Range 2 kV isolation 60 A to 60 kA 70 mHz to 1 MHz

RCTi & RCTi-3ph For permanent installation 2 kV isolation 250 A to 50 kA 0.2 Hz to 1 MHz PEM Rogowski Coils have a lot of Flexibility and can be Customized Almost any coil length Low Freq can be tailored **GMWAssociates** 

### New "Forked" PEM Rogowski Coil

#### • CWTUM-F / CTWUMHF-F

- 55 mm length
- 1.2 mm & 1.7 mm (HF) cross-section
- 1.2 kV isolation
- 60 A to 12 kA
- 1.2 Hz to 20 MHz and 30 MHz (HF)





### PEM Common Mode Current Rogowski Coil

- Probe for measuring **HF common mode current** in **VSDs**
- High LF bandwidth to attenuate large fundamental freq
- HF Bandwidth **10+ MHz** (up to 50 MHz)
- 37.5 A to 150 A







### Rogowski Coil Pitfalls

- AC-only
- **Damage** can occur due to excessive  $\frac{dI_p}{dt}\Big|_{pk}$  and/or  $\frac{dI_p}{dt}\Big|_{rms}$  not absolute current  $I_p$
- For high  $\frac{dV}{dt}$  applications there are version with electrostatic screen around coil to reduce noise
- Primary current cable should not be position close to the coil-cable junction
- Very thin Rogowski Coils (Ultra Mini) need care to avoid damage (no sharp bends or edges)
- The longer the coil, the lower  $\omega_H$
- The lower current rating, the higher  $\omega_L$



POSITIONAL ACCURACY OF A STANDARD ROGOWKSI COIL -% error with a point source of current

Туре	Α	в	с
Miniature Coil	±0.5%	±1%	±3%
Standard Coil	±0.5%	±1%	±2%

The current should not be positioned close to the coil-cable junction (shown by the shaded area) since the error for this region is greater.

## Closed-Loop Flux-Gate DCCTs

For High-Precision DC & AC Measurements

### Closed-Loop or Zero-Flux Concept

- Flux Sensor senses Flux in Core
  - Hall-Effect Sensor in Gap (Low-precision due to gap)
    - Temperature changes causes Mechanical changes
    - Sensitivity to external fields due to gap
  - Coil (Hereward Transformer, AC Only)
  - Flux-gate (most precise)
- Feedback loop maintains Zero-Flux in Core
  - Generates opposing current *I<sub>C</sub>* into *N* turns
- $I_p$  measured through secondary current  $I_C = \frac{I_p}{N}$
- *I<sub>C</sub>* measured **directly** or through **burden resistor** *R<sub>B</sub>* 
  - Typically with DMM or Power Analyzer





#### Flux-Gate Concept



### Closed-Loop Flux-Gate

- Modulating core  $\mu$  generates 2<sup>nd</sup> harmonic  $\propto I_p$
- Demodulated 2<sup>nd</sup> Harmonic drives compensation loop
- $I_p$  measured through secondary current  $I_C = \frac{I_p}{N}$
- $I_C$  measured **directly** or through **burden resistor**  $R_B$
- Frequency Mixing Process due to Core Non-Linearity:
  - Modulating core  $\mu$  with  $f_{OSC}$  up-mixes  $H_p$  spectrum to 2  $f_{OSC}$
  - 2<sup>nd</sup> Harmonic detector **down-mixes** *I*<sub>C</sub> to baseband
- This does not work as is:
  - Temperature drifts
  - Excitation breakthrough

 $2^{nd}$  Harmonic Demodulation  $-2f_{OSC}$   $H_p$   $I_C$   $I_{OSC}$   $I_{OSC}$   $\mu$  Modulation



### 2-Core Flux-gates

- Single-core flux-gates suffer from
  - Temperature drifts
  - Excitation breakthrough to the output
- 2 matched cores to cancel drifts and excitation
  - Cores Modulated in opposition
  - Demodulated 2<sup>nd</sup> harmonic difference drives *I<sub>C</sub>*
  - Reduced cross-talk to other sensor (e.g. 3ph system)
- Many different excitation / demodulation circuits



### Mathematical Analysis of the Flux-Gate

- B-field in the two cores:  $\begin{aligned} B' &= f \big( H_p + H_{OSC} \big) \\ B'' &= f \big( H_p H_{OSC} \big) \end{aligned}$
- Sense coil  $\mathcal{EMF} = -NA\frac{d}{dt}(B' + B'')$
- If B = aH, then  $B' + B'' = 2aH_p$ , and  $\mathcal{EMF} = -2aNA\frac{d}{dt}H_p = 0$ 
  - Flux-gates depend on the core non-linearity
- If  $B = aH bH^3$ , then  $B' + B'' = 2aH_p 2bH_p^3 6bH_pH_{OSC}^2$ 
  - $\mathcal{EMF} = 6bNAH_p \frac{d}{dt} H_{OSC}^2 \neq 0$
  - If  $H_{OSC} \propto \sin \omega t$  then  $\mathcal{EMF} \propto \sin 2\omega t$
  - Note this is a simplified core model for qualitative analysis





#### Extending the Frequency Response

- Flux-Gate **BW** on the order of 100 Hz 1 kHz
- 3<sup>rd</sup> Core in AC CT configuration up to MHz
- Compensating Amplifier sums LF and HF
- Four frequency regions:
  - Near DC: Flux-gate and Amp drives I<sub>C</sub>
  - Low-Freq: Amp sums Flux-Gate + ACCT drive I<sub>C</sub>
  - Medium-Freq: Amp + ACCT drive I<sub>C</sub>
  - High-Freq: Amp Unity Gain ACCT + R<sub>B</sub> as Passive CT



#### Danisense Closed-Loop Flux-Gate DCCTs



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### Danisense DW500UB-10V – Highest Frequency DCCT

- Highest BW Closed-Loop Flux-Gate DC 10 MHz (3dB)
- Up to 500 A DC/AC
- 2 V output (250 A/V ratio)





### **Danisense Residual Current Monitor**

- B/B+ Residual Current Monitor
  - 0 2 Arms
  - DC to 100 kHz
- 4 20 mA output for monitoring with PLC
- Relay output can trip breaker or contactor
- Model with USB for PC control and data logging



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Pinout:

1: 24Vdc

5: 0Vdc

7: 0Vdc

2: Relay common 3: 0Vdc

4: Relay NC contact

6: Relay NO contact

8: External Test button, contact 1 9: Analog 4-20mA output

10: External Test button, contact 2

### Bergoz IPCT – High Resolution DCCT

- Custom Full-scale from 1 mA to 20 A
- DC to 3.8 kHz (3dB)
- 10 V output
- Zero-offset potentiometer
- 82 mm Aperture accommodates Large Connectors or use in differential mode for residual current (e.g. x-ray tube)



### Closed-Loop Flux-Gate DCCT Pitfalls

- Opening the DCCT Secondary can lead to transducer damage.
  - Danisense DCCTs have internal protection but many other DCCTs in the market do not.
- Persistent over-current will cause damage.
- An over-current spike will cause oscillations that dampen within milliseconds.
- Turn-on history has a small effect due to core hysteresis causing small zero-offset drifts.
- Excitation frequency will have a small breakthrough signal to the output.
- Compensation current comes from Transducer power supply, make sure it has enough oomph
- Susceptivity to external magnetic fields
  - Flux-gate DCCTs are less susceptible than Closed-Loop Hall Effect with gap but not completely immune



## Hall Effect Sensors

For DC & AC Measurements

### Hall Effect Sensors

- Hall Effect is production of Voltage across conductor in magnetic field transverse to current
  - Arises from Lorentz Force on charge carriers
- Hall Element:
  - Typically p-type semiconductor

• 
$$V_H = R_H \left(\frac{I}{t} \times B\right)$$

- *R<sub>H</sub>* is Hall Effect coefficient (material-dependent)
- t is material thickness

#### Hall Sensor:

- Integrated Hall Element + Voltage Regulator + Amplifier
- Output saturates near supply voltage and ground





#### Senis BBM

- Two interconnected Hall Sensors as a Busbar current transducer.
  - Sensitivity depends on Busbar geometry but output needs calibration
  - External currents mostly rejected depending on orientation •
  - Needs engineering effort from user
- 5 V supply
- $0 \pm 4 V$  output
- DC only (AC affected by busbar geometry) •  $H(I,w,h) \approx \frac{I}{2(w+2h)}$

W

Clean recovery from overload

### **GMW**Associates

#### GMW CPC/CPCO



GMW CPC 250 A to 2 kA 1% accuracy 27 mm aperture -40 degC to 100 degC DC to 75 kHz 5 V supply  $0 \pm 2$  V output

#### 25 A in development

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**GMW CPCO** 500 A to 16 kA 1% accuracy 77 or 160 mm aperture -40 degC to 100 degC DC to 40 kHz 5 V supply  $5 \pm 5$  V,  $0 \pm 5$  V,  $0 \pm 10$  V, RMS 0 - 3 V, 4 - 20 mA output

20 A (77mm) in development

GMW CSS-SO 400 A to 12 kA 1% accuracy 102mm x 30.2 mm aperture DC to 1 kHz 5 V supply  $0 \pm 2$  V output

### GMW CPC/CPCO Principle of Operation

- Ampere's Law:  $\oint \mathbf{B} \cdot d\mathbf{l} = \mu_0 I_{enc}$ 
  - Independent of position of the current
- Discretize Ampere's Law  $I_{enc} = \frac{1}{\mu_0} \oint \boldsymbol{B} \cdot d\boldsymbol{l} \approx \frac{1}{\mu_0} \sum_{i=1}^n C_i B_i$ 
  - $B_i$  is tangential field component at point i
  - C<sub>i</sub> are constants determined by magnetic modeling
- · Currents external to the integration path are rejected
  - More sensors result in better rejection



#### US Patents: 9952257, 10690701 European Patent: 2972425

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### Recovery from Overload

With 4x primary overload current the CPC shows:

• No electrical saturation, correct sign, no overshoot

"Ju

Tek

CH1 2.00V

- No ringing
- No zero-crossing phase shift after overload
- No damage



10.0mV

Green Trace

Yellow Trace

CPC ±250A fs with 750Arms Primary Current (yellow trace), or ±1060A. Approx. 4x full scale.

AC Line J 0.00V

60.0144Hz

M 5.00ms

28-Apr-21 06:38

CH4 100mV

### **GMW**Associates

M 5.00, us

CH4 2.00mVBy 28-Apr-21 06:32

AC Line / 0.00V

60.0013Hz

## **Common Issues**

## Transducer Termination

For Voltage-Output Transducers

### **Problem Overview**

- Often asked about:
  - Factor of 2 discrepancies in measurements due to improper termination
  - Coaxial cable reflections when terminating into High-Impedance
  - There is often confusion between **Source** and **Termination Impedance**
- Always Check the Manual for the Proper Termination Impedance!
- We need to analyze the signal propagation in a coaxial cable terminated into 50  $\Omega$  and 1 M $\Omega$ 
  - Only applicable to Voltage-Output transducers



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### **Electrical Length**



-O	$\longrightarrow$
$\checkmark$	



Frequency	Free-Space $\lambda_0$	Notes
60 Hz	5,000 km	AC power distribution freq in North America.
1 kHz	300 km	
75 kHz	4 km	Typical power converter switching frequency.
1 MHz	300 m	
10 MHz	30 m	Highest frequency <b>Danisense</b> transducer.
50 MHz	6 m	Highest frequency <b>PEM</b> Rogowski Coil.
500 MHz	60 cm	Highest frequency MagneLab CT.
1.5 GHz	20 cm	Highest frequency <b>Bergoz</b> FCT.
2.45 GHz	12 cm	Typical microwave oven magnetron frequency.

Wavelength refers to the highest frequency of interest



#### Methods of Analysis

- Lumped Element or Circuit Analysis
  - Mathematical approximation to Maxwell's equations
  - Problem can be decomposed into ideal circuit elements (resistors, capacitors, inductors)
  - Ignore finite speed of light
- Transmission Line Theory
  - Another Mathematical approximation to Maxwell's equations
  - Problem can be decomposed into transmission lines & ideal circuit elements
  - EM waves propagate in Transmission Lines with finite speed
  - Any junction can cause reflections
  - Yields same results as Circuit Analysis in electrically small problems



### **Transmission Line Theory**

• **Transmission Line:** physical structure that guides EM waves without reflection or mode conversion (e.g. coax, rect waveguide)

 $V(z,t) = V_0^+ e^{j(2\pi ft - \beta z)} + V_0^- e^{j(2\pi ft + \beta z)}$  $I(z,t) = I_0^+ e^{j(2\pi ft - \beta z)} - I_0^- e^{j(2\pi ft + \beta z)}$ 

- Transmission Line Properties:
  - Wave impedance  $Z_0 = \frac{V_0^{\pm}}{I_0^{\pm}} = \sqrt{\frac{L_l}{C_l}}$
  - Propagation constant  $\beta = \frac{2\pi}{\lambda_g}$ , where  $\lambda_g$  is guided wavelength
- Minus sign in front of  $I_0^-$  sets power flow direction  $S = E \times H$







#### **Reflections In Transmission Lines**

- Terminating into  $Z_L \neq Z_0$  causes reflection  $\Gamma_L = \frac{V_0^-}{V_0^+} = \frac{Z_L Z_0}{Z_L + Z_0}$
- Voltage across the line is function of position (standing wave)  $V(z) = V_0^+ e^{-j\beta z} (1 + \Gamma_L e^{j2\beta z})$
- Impedance from the input side becomes a function of the length  $Z_{in} = Z_0 \frac{Z_L + jZ_0 \tan(\beta L)}{Z_0 + jZ_L \tan(\beta L)}$
- Electrically short transmission lines are transparent  $\lim_{\beta L \to 0} Z_{in} = Z_L$



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### Terminating into $50 \Omega$

- Transmission Line Analysis:
  - Impedance seen from point B is  $50 \ \Omega$
  - Voltage divider at point B launches wave with half amplitude
  - Wave fully absorbed at load
  - Measured voltage is half



- Circuit Analysis:
  - Coax replaced by short-circuit
  - Measured voltage is half because of voltage divider



### Terminating into High-Impedance

#### Transmission Line Analysis:

- Voltage divider at point B launches wave with half amplitude (initially)
- Wave fully reflected at load
- Voltage at point C is sum of Forward and Reverse wave amplitudes
- Measured voltage is full
- · Reflected wave cause standing wave but fully absorbed at source



#### • Circuit Analysis:

- Coax replaced by short-circuit
- Measured voltage is full because of voltage divider



#### **Miscellaneous Considerations**

- Oscilloscope Termination Impedance:
  - Mid & Low-end scopes only have high-impedance input for 50  $\Omega$  need BNC feedthrough termination or BNC Tee and 50  $\Omega$  termination on one end
  - High-End scopes have both options check that you use the appropriate
  - High BW scopes only have 50  $\Omega$  input for high impedance you need active high-impedance adapter
- Bandwidth & Time Domain Specs:
  - For Transducers that work with high-impedance and 50  $\Omega$ , specs only guaranteed for one of the two
- There are non-50  $\Omega$  BNC cables and connectors
  - If length comparable to wavelength, then accuracy is affected



## **Uncertainty Analysis**

For precision measurements

### Measurement Uncertainty Overview

- Need to determine **best estimate**  $\overline{X}$  of quantity X referred to as **measurand** 
  - The measurement has **uncertainty** *u*(*X*)
  - **True value** of measurand lies in the interval  $\overline{X} \pm u(X)$
  - Note:  $\overline{X}$  and u(X) have same units!
- Two types of uncertainty:
  - **Type A:** due to statistical nature of measurement take 10 samples  $u_A(X) = STD(X_1, ..., X_{10})$
  - **Type B:** determined by other means instrument accuracy specs or calibration certificate
- Combined uncertainty:  $u_C(X) = \sqrt{u_A^2(X) + u_B^2(X)}$
- Expanded uncertainty:  $u(X) = k \cdot u_C(X)$ 
  - k = 2 for 95% coverage
- **Numerical example:** We are measuring  $\sim 2$  A with a DMM
  - From the DMM cal cert for 3 A range  $u(X) = 3 \cdot 10^{-4} \text{ A} \rightarrow u_B(X) = u(X)/2 = 1.5 \cdot 10^{-4} \text{ A}.$
  - We take 10 samples with mean  $\overline{X} = 1.9995$  A and STD  $u_A(X) = 2.9 \cdot 10^{-4}$  A
  - The combined uncertainty is  $u_C(X) = 3.3 \cdot 10^{-4} \text{A} \rightarrow u(X) = 2 \cdot u_C(X) = 6.6 \cdot 10^{-4} \text{A}$
  - **True value** lies in interval  $1.9995 \pm 0.00066$  A



### What about Measurements with Multiple Instruments?

- We need model of the measurement  $Y = f(X_1, ..., X_m)$ 
  - *Y* is measurand
  - $X_1, \dots, X_m$  are sub-quantities we measure directly as before
- For each sub-quantity we calculate combined uncertainty  $u_C(X_1), \dots, u_C(X_m)$
- Linearize model around best estimate point  $\overline{Y} = f(\overline{X_1}, ..., \overline{X_m})$ 
  - Calculate sensitivity coefficients  $\frac{\partial Y}{\partial X_i}$
  - **Propagate** combined uncertainties  $u_C^2(Y) = \sum_i \left(\frac{\partial Y}{\partial X_i}\right)^2 u_C^2(X_i)$
- Expanded uncertainty  $u(Y) = k \cdot u_C(Y)$
- **True value** of measurand lies in the interval  $\overline{Y} \pm u(Y)$



### Measuring Current with a Current Transducer and DMM

- Need to measure current with a DCCT and DMM
- DCCT has output X<sub>o</sub> measured on DMM
- DCCT has true ratio  $K = \frac{K_r}{1+\epsilon}$ 
  - $K_r$  is the rated ratio from manufacturer's spec
  - $\epsilon$  is the ratio error found in the DCCT calibration certificate
- From the DMM and transducer K, primary current is  $I_p = KX_o$
- The model of the measurement is  $I_p = \frac{K_r X_o}{1+\epsilon}$
- We take *n* measurements of  $X_o$  best estimate for DCCT output is  $\overline{X_o} = \langle X_o^{(i)} \rangle$
- **Best estimate** of primary current is  $\overline{I_p} = \frac{K_r \overline{X_o}}{1+\epsilon} \approx K_r \overline{X_o}$







### Uncertainty Analysis

- Sources of Uncertainty:
  - **Combined** uncertainty of the **DCCT output**  $u_C(X_o)$
  - Type B uncertainty of the DCCT ratio error  $u_B(\epsilon)$
- **Combined** uncertainty of the **DCCT output**  $u_C(X_o) = \sqrt{u_A^2(X_o) + u_B^2(X_o)}$ 
  - **Type A** uncertainty  $u_A^2(X_o) = \frac{1}{n-1} \sum_{i=1}^n \left( X_o^{(i)} \overline{X_o} \right)^2$
  - **Type B** uncertainty  $u_B(X_o)$  from the accuracy specs or calibration certificate of the DMM
- Primary current sensitivity coefficients:
  - $\frac{\partial I_p}{\partial X_o} = \frac{K_r}{1+\epsilon}$
  - $\frac{\partial I_p}{\partial \epsilon} = \frac{K_r X_o}{(1+\epsilon)^2}$
- **Combined** uncertainty of primary current  $u_C(I_p) = \sqrt{\left(\frac{\partial I_p}{\partial X_o}\right)^2 u_C^2(X_o) + \left(\frac{\partial I_p}{\partial \epsilon}\right)^2 u_B^2(\epsilon)}$
- **Expanded** uncertainty of primary current  $u(I_p) = k u_c(I_p)$

#### Instrument Uncertainties & Setup

- Two options for **Type B** instrument uncertainties  $u_B(X_o)$  and  $u_B(\epsilon)$ :
  - **Manufacturer's specifications** given as % *Reading* + % *Range* 
    - Calculate expanded uncertainty  $u(X) = \epsilon_{reading} X_{reading} + \epsilon_{range} X_{range}$
    - Calculate Type B uncertainty  $u_B(X) = u(X)/k$

#### Calibration Certificate

- Interpret numbers as expanded uncertainty
- Calculate Type B uncertainty  $u_B(X) = u(X)/k$
- Note: When instrument has multiple ranges, need uncertainty of active range!
  - It's better to manual set the instrument range than use Autorange



### Numerical Example

- We are measuring  $\sim$ 3 kA with a current-output DCCT and a DMM
- DCCT with rate ratio  $K_r = 1500$ 
  - From the calibration certificate  $\epsilon = -23$  ppm and  $u(\epsilon) = 0.1\% \rightarrow u_B(\epsilon) = u(\epsilon)/2 = 0.5 \cdot 10^{-3}$
- DMM in the 3 A range (expect  $\sim 2$  A)
  - From the calibration certificate  $u(X_o) = 3 \cdot 10^{-4} \text{ A} \rightarrow u_B(X_o) = u(X_o)/2 = 1.5 \cdot 10^{-4} \text{ A}$
- We take n = 10 measurements with the DMM
  - Mean value  $\overline{X_o} = 1.9995$  A results in best estimate of primary current  $\overline{I_p} = 2999.32$  A
  - Sample STD  $u_A(X_o) = 2.9 \cdot 10^{-4} \text{ A}$
- Transducer output combined uncertainty  $u_C(X_o) = \sqrt{u_A^2(X_o) + u_B^2(X_o)} = 3.3 \cdot 10^{-4} \text{ A}$
- Sensitivity coefficients  $\frac{\partial I}{\partial X_o} = \frac{K_r}{1+\epsilon} = 1500.03$  and  $\frac{\partial I}{\partial \epsilon} = \frac{K_r X_o}{(1+\epsilon)^2} = 2999.39$  A
- Propagate  $u_C(I_p) = \sqrt{\left(\frac{\partial I_p}{\partial X_o}\right)^2 u_C^2(X_o) + \left(\frac{\partial I_p}{\partial \epsilon}\right)^2 u_B^2(\epsilon)} = 1.58 \text{ A and } u(I_p) = 2 \cdot u_C(I_p) = 3.15 \text{ A}$
- True value of primary current lies in interval 2999.32  $\pm$  3.1 A

### **Other Measurement Models**

#### **DC Offset**

- When measuring **DC current**, transducer may exhibit **small zero current offset** Xoff
  - Flux-gate DCCT Turn-on history causes small zero-offset drifts.
- Model of Measurement with Offset:  $I_p = \frac{K_r(X_o X_{off})}{1 + \epsilon}$ 
  - Added combined uncertainty of zero current offset measurement

#### Using a Burden Resistor

- Often DMM voltage channel has better accuracy than current
  - It may be preferable to measure voltage drop  $V_o$  on burden resistor  $R_B$
- Model of Measurement with Burden Resistor:  $I_p = \frac{K_r}{1+\epsilon} \frac{V_o}{R_B}$ 
  - Added Type B uncertainty of burden resistor value



#### GMW 17025 Accredited Calibration Certificate

#### **GMW Current Calibration Services:**

- DC Amplitude up to 11 kA & AC Amplitude & Phase up to 8 kA and up to 400 Hz •
- **10 days Typical Turnaround** •
- **Onsite Calibration Services** •





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- Apr 01, 2024 - Feb 15, 2024

## **Further Reading**

### **Further Reading**

#### **General Current Measurement:**

- Bastos, M. C. (2016). High precision current measurement for power converters. arXiv preprint arXiv:1607.01584. https://arxiv.org/pdf/1607.01584
- Webber, R. C. (1995, May). Charged particle beam current monitoring tutorial. In AIP Conference Proceedings CONF- 9410219 (Vol. 333, No. 1, pp. 3-23). American Institute of Physics. <a href="https://inis.iaea.org/collection/NCLCollectionStore/">https://inis.iaea.org/collection/NCLCollectionStore/</a> Public/26/033/26033463.pdf
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#### Active (Hereward) Transformer:

• Sharp, J. B. (1962). The induction type beam monitor for the PS: Hereward transformer (No. MPS-Int-CO-62-15). https://cds.cern.ch/record/1068123/files/cer-002723994.pdf

#### **Rogowski Coils:**

 Ray, W. F., & Hewson, C. R. (2000, October). High performance Rogowski current transducers. In Conference Record of the 2000 IEEE Industry Applications Conference. Thirty-Fifth IAS Annual Meeting and World Conference on Industrial Applications of Electrical Energy (Cat. No. 00CH37129) (Vol. 5, pp. 3083-3090). IEEE. <u>https://citeseerx.ist.psu.edu/document?repid=rep1&type=pdf&doi=83bfb38f5370c6744240b21d12f7f1b0fddb0d33</u>

#### Fluxgate DCCTs:

- Unser, K. B. (1992, April). The parametric current transformer, a beam current monitor developed for LEP. In AIP Conference Proceedings (Vol. 252, No. 1, pp. 266-275). American Institute of Physics. <u>https://cds.cern.ch/record/231598/files/CM-P00061084.pdf</u>
- Musmann, G. (Ed.). (2010). Fluxgate magnetometers for space research. BoD–Books on Demand.
- Geyger, W. A. (1954). *Magnetic-amplifier circuits: basic principles, characteristics, and applications*. McGraw-Hill.



### **Further Reading**

#### **Transducer Termination / Transmission Line Theory:**

- Toufexis, F. (2024). GWM Application Note: Transducer Termination Impedance Low and High Frequency Analysis. <u>https://gmw.com/wp-content/uploads/2024/09/ftouf\_CTTerminationTransLine\_AppNote\_240925.pdf</u>
- Pozar, D. M. (2021). *Microwave engineering: theory and techniques*. John wiley & sons.
- Collin, R. E. (2007). Foundations for microwave engineering. John Wiley & Sons.

#### **Uncertainty Analysis:**

- Toufexis, F. (2024). GWM Application Note: Estimating the Current Measurement Uncertainty when utilizing Current Transducers. https://gmw.com/wp-content/uploads/2023/04/ftouf\_CurrentUncertainty\_AppNote\_240925.pdf
- Taylor, J. R. (1997). An Introduction to Error Analysis: The Study of Uncertainties in Physical Measurements.
- Crowder, S., Delker, C., Forrest, E., & Martin, N. (2020). Introduction to statistics in metrology. Cham, Switzerland: Springer.
- <u>https://www.bipm.org/en/publications/guides/</u>



## **Thank You!**



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